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U.S. UTILITY Patent Application

PATENT NUMBER and
ISSUE DATE

APPL NUM	FILING DATE	CLASS	SUBCLASS	CAU	EXAMINER
10082288	02/26/2002	250	2878	2878	02/26/02

**APPLICANTS: Sato Mitsugu; Otake Tadashi; Ezumi Makoto; Takane Atsushi; Yoshida Shoji; Yamaguchi Satoru; Ozawa Yasuhiko;

**CONTINUING DATA VERIFIED:

** FOREIGN APPLICATIONS VERIFIED:

JAPAN 2001-161588 05/30/2001

JAPAN 2001-208674 07/10/2001

PG-PUB DO NOT PUBLISH ☐

RESCIND ☐

Foreign priority claimed

35 USC 119 conditions met

Verified and Acknowledged Examiners's initials

ATTORNEY DOCKET NO

H6808.0005/P005

TITLE : Charged particle beam alignment method and charged particle beam apparatus

U.S. DEPT. OF COMM /PAT. & TM-PTO-436L/Rev. 12-94

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DRAWINGS			CLAIMS ALLOWED	
Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
			NOTICE OF ALLOWANCE MAILED	
(Assistant Examiner) (Date)				
			ISSUE FEE	
			Amount Due	Date Paid
(Primary Examiner) (Date)				
			ISSUE BATCH NUMBER	
(Legal Instruments Examiner) (Date)				